

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	688	361/234.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/06/01 12:47
S6	16	(("20010016302") or ("20020067585") or ("5117121") or ("6033482") or ("6567257") or ("20030030961") or ("6552892") or ("6529362")).PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2006/05/31 14:00
S7	98951	(wafer workpiece) same (doping etching implantation)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/05/31 15:41
S8	3470	S7 same (bias biasing)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/05/31 15:35
S9	1440	S8 same (voltage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/05/31 15:35
S10	9	S9 same (lift\$3 adj pin\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/05/31 15:34
S11	137	S7 same (lift\$3 adj pin\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/05/31 15:42
S12	43	S11 same electrode	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/05/31 15:35
S13	10	S12 same (voltage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/05/31 15:35
S14	0	S13 same (bias biasing)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/05/31 15:35
S15	19769	(wafer workpiece) same (bias biasing)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/05/31 15:41
S16	79	S15 same (lift\$3 adj pin\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/05/31 15:57

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S17	2	("6,454,898").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2006/05/31 15:57
S18	2	("4551192").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2006/05/31 18:07
S19	4	("4004955" "4313783" "4339297" "4439261").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/05/31 18:22
S20	29	("4551192").URPN.	USPAT	OR	ON	2006/05/31 18:30
S27	15	("4357006") or ("4551192") or ("5796066") or ("5810933") or ("6628503") or ("6806007") or ("20050207089").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	OFF	2006/05/31 18:40
S28	28	(esc ((electrostatic electro\$static (electro adj static)) adj (chuck\$3 clamp\$3 hold\$3)) chuck) and (bias\$3 same voltage near3 pin)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/05/31 18:42
S29	28	(esc ((electrostatic electro\$static (electro adj static)) adj (chuck\$3 clamp\$3 hold\$3)) chuck) and (bias\$3 same voltage near3 pin\$2)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/05/31 18:50
S30	31	(esc ((electrostatic electro\$static (electro adj static)) adj (chuck\$3 clamp\$3 hold\$3)) chuck) and (bias\$3 same (source voltage) near3 pin\$2)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/06/01 13:09
S31	48	(esc ((electrostatic electro\$static (electro adj static)) adj (chuck\$3 clamp\$3 hold\$3)) chuck) and (high same (voltage) near3 pin\$2)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/05/31 19:12
S32	278	(esc ((electrostatic electro\$static (electro adj static)) adj (chuck\$3 clamp\$3 hold\$3)) chuck) and ((source voltage) near3 pin\$2)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/05/31 19:44
S33	102	(esc ((electrostatic electro\$static (electro adj static)) adj (chuck\$3 clamp\$3 hold\$3)) chuck) and ((source voltage) near3 pin\$2) and (bias biasing)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/05/31 19:37
S34	76596	((((plasma) with (etching doping)) plad)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/05/31 19:42
S35	3608	S34 same (high with (voltage energy))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/05/31 19:43

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S36	1038	S35 same (wafer workpiece)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/05/31 19:43
S37	14	S36 same (esc ((electrostatic electro\$static (electro adj static)) adj (chuck\$3 clamp\$3 hold\$3)) chuck) and ((lift\$3) near3 pin\$2)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/05/31 19:54
S38	28090	S36 ((lift\$3) near3 pin\$2)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/05/31 19:51
S39	8	S36 same lift\$3 adj pin\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/05/31 19:52
S40	159	S34 same (esc ((electrostatic electro\$static (electro adj static)) adj (chuck\$3 clamp\$3 hold\$3)) chuck) and ((lift\$3) near3 pin\$2)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/05/31 19:59
S41	105	S40 and ((high bias biasing) near3 voltage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/05/31 20:00
S45	517	279/128.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/06/01 12:48
S47	7	(esc ((electrostatic electro\$static (electro adj static)) adj (chuck\$3 clamp\$3 hold\$3)) chuck) and (bias\$3 same (source voltage) near3 pin\$2)	US-PGPUB	OR	ON	2006/06/01 13:10
S48	6	(esc ((electrostatic electro\$static (electro adj static)) adj (chuck\$3 clamp\$3 hold\$3)) chuck) with (bias\$3 same (source voltage) with (lift\$3 adj pin\$2))	US-PGPUB	OR	ON	2006/06/01 13:11
S51	1	(bias\$3 adj3 (source voltage)) and (lift\$3 adj pin\$2) and (workpiece) and (wafer adj platen)	US-PGPUB	OR	ON	2006/06/01 13:14